Power MOSFET30 V, 66 A, Single N-Channel, SO-8FL

Features

- Low R_{DS(ON)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These are Pb-Free Devices

Applications

- Refer to Application Note AND8195/D
- CPU Power Delivery
- DC-DC Converters

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Par	Symbol	Value	Unit		
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Vol	Gate-to-Source Voltage			±20	V
Continuous Drain Current R _{0.1A}		T _A = 25°C	I _D	15	Α
(Note 1)		T _A = 85°C		11	
Power Dissipation R _{0JA} (Note 1)		T _A = 25°C	P _D	2.17	W
Continuous Drain		T _A = 25°C	ID	9.5	Α
Current R _{θJA} (Note 2)	Steady	T _A = 85°C		7.0	
Power Dissipation R _{0JA} (Note 2)	State	T _A = 25°C	P _D	0.87	W
Continuous Drain Current Raic		T _C = 25°C	I _D	66	Α
(Note 1)		T _C = 85°C		48	
Power Dissipation R _{θJC} (Note 1)		T _C = 25°C	P _D	41.7	W
Pulsed Drain Current		= 25°C, = 10 μs	I _{DM}	132	Α
Operating Junction and Storage Temperature			T _J , T _{STG}	-55 to +150	°C
Source Current (Body Diode)			I _S	35	Α
Drain to Source DV/DT			dV/dt	6	V/ns
Single Pulse Drain-to-Source Avalanche Energy T_J = 25°C, V_{DD} = 30 V, V_{GS} = 10 V, I_L = 19 A_{pk} , L = 1.0 mH, R_G = 25 Ω			EAS	180.5	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

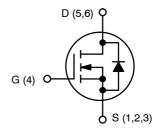
- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.



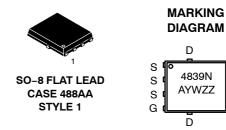
ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX	
30 V	5.5 mΩ @ 10 V	00.4	
	9.5 mΩ @ 4.5 V	66 A	



N-CHANNEL MOSFET



A = Assembly Location

D

D

Y = Year
W = Work Week
ZZ = Lot Traceavility

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMFS4839NT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NTMFS4839NT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	3.0	
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	57.7	°C/W
Junction-to-Ambient - Steady State (Note)	$R_{\theta JA}$	143.4	

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•			•	•	•	
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				25		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25 °C			1	_
		V _{DS} = 24 V	T _J = 125°C			10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 V, V_{GS}$	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$	= 250 μA	1.5		2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.8		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V to	I _D = 30 A		4.5	5.5	
		11.5 V	I _D = 15 A		4.5		
		V _{GS} = 4.5 V	I _D = 30 A		8.4	9.5	mΩ
			I _D = 15 A		8.4		
Forward Transconductance	9FS	V _{DS} = 15 V, I _D	= 15 A		14.7		S
CHARGES, CAPACITANCES & GATE RESIS	TANCE			•	•	•	
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 12 V			1588		pF
Output Capacitance	C _{OSS}				352		
Reverse Transfer Capacitance	C _{RSS}				196		
Total Gate Charge	Q _{G(TOT)}				13	18	
Threshold Gate Charge	Q _{G(TH)}	V _{GS} = 4.5 V, V _{DS} = 15 V; I _D = 30 A			1.6		nC
Gate-to-Source Charge	Q_{GS}				4.8		
Gate-to-Drain Charge	Q_{GD}				5.8		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 11.5 V, V _{DS} = 15 V; I _D = 30 A			28		nC
SWITCHING CHARACTERISTICS (Note 6)							
Turn-On Delay Time	t _{d(ON)}				12		
Rise Time	t _r	V_{GS} = 4.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			29		ns
Turn-Off Delay Time	t _{d(OFF)}				18		
Fall Time	t _f				7.0		
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 11.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			8.0		
Rise Time	t _r				21		1
Turn-Off Delay Time	t _{d(OFF)}				24		ns
Fall Time	t _f				7.0		1

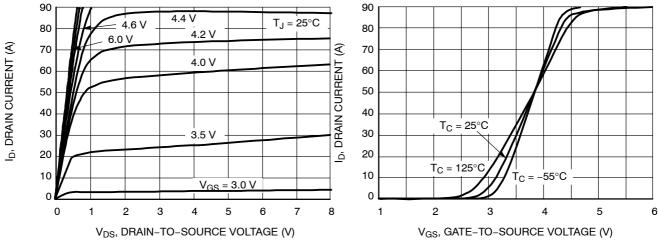
Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

^{5.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
6. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit	
DRAIN-SOURCE DIODE CHARACTERISTICS								
Forward Diode Voltage	V_{SD}	VGS = 0 V,	T _J = 25°C		0.9	1.2	V	
			T _J = 125°C		0.8			
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, dIS/dt = 100 A/μs, I _S = 30 A			22.2		ns	
Charge Time	t _a				12.5			
Discharge Time	t _b				9.7			
Reverse Recovery Charge	Q _{RR}				10.8		nC	
PACKAGE PARASITIC VALUES								
Source Inductance	L _S	T _A = 25°C			0.93		nΗ	
Drain Inductance	L _D				0.005		nΗ	
Gate Inductance	L _G				1.84		nΗ	
Gate Resistance	R_{G}				3.3		Ω	

- 5. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
- 6. Switching characteristics are independent of operating junction temperatures.





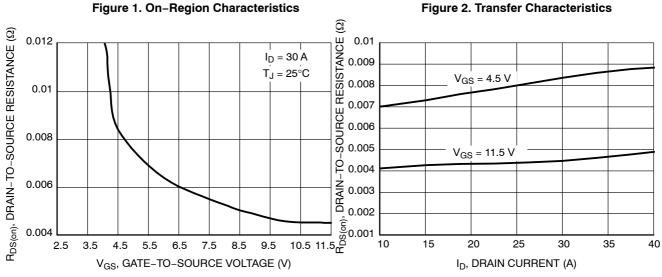


Figure 3. On-Resistance versus Gate-to-Source Voltage

Figure 4. On-Resistance versus Drain Current and Temperature

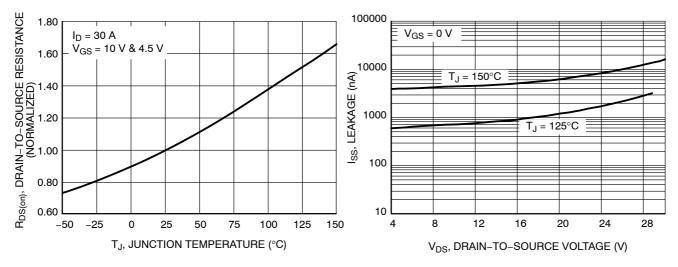
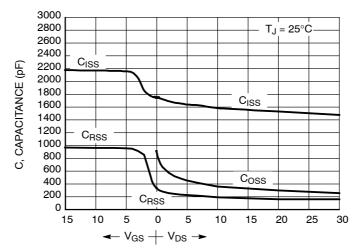


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current versus Voltage



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (V)

Figure 7. Capacitance Variation

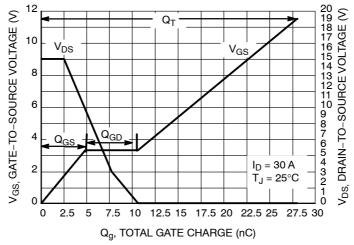


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Gate Charge

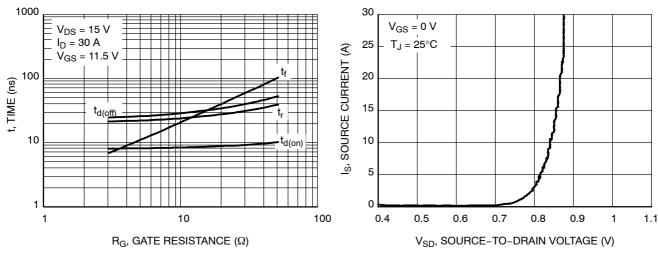


Figure 9. Resistive Switching Time Variation versus Gate Resistance

Figure 10. Diode Forward Voltage versus Current

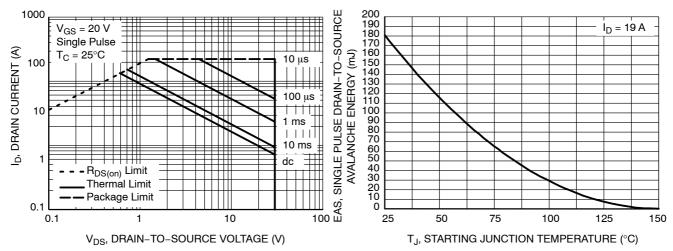
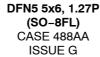
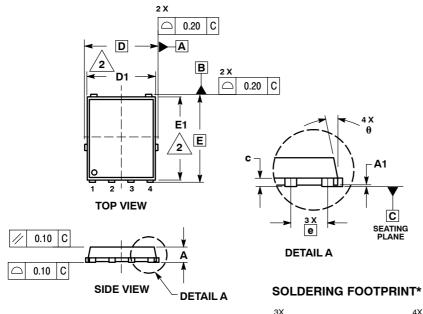


Figure 11. Maximum Rated Forward Biased Safe Operating Area

Figure 12. Maximum Avalanche Energy versus Starting Junction Temperature

PACKAGE DIMENSIONS





NOTES:

- DIMENSIONING AND TOLERANCING PER
 - ASME Y14.5M, 1994.
 CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS					
DIM	MIN	NOM	MAX			
Α	0.90	1.00	1.10			
A1	0.00		0.05			
b	0.33	0.41	0.51			
С	0.23	0.28	0.33			
D		5.15 BSC	;			
D1	4.50	4.90	5.10			
D2	3.50		4.22			
E	6.15 BSC					
E1	5.50	5.80	6.10			
E2	3.45		4.30			
е		1.27 BSC				
G	0.51	0.61	0.71			
K	1.20	1.35	1.50			
L	0.51	0.61	0.71			
L1	0.05	0.17	0.20			
M	3.00	3.40	3.80			
θ	0 °		12 °			

- STYLE 1: PIN 1. SOURCE
 - 2. SOURCE
 - 3. SOURCE GATE
- <−0.750 8x b 0.10 С Α В .000 Ф e/2 0.05 C 0.965 Κ 1.330 0.905 2X F2 0.495 -PIN 5 (EXPOSED PAD) М 4.530 3.200 0.475 D2 G 2X **BOTTOM VIEW** → 1.530

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

4.560

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